



RADIO TEST REPORT

Test Report No. : 12656071S-V-R1

Applicant : Nintendo Co., Ltd.
Type of Equipment : Game Console
Model No. : HDH-002
FCC ID : BKEHDH002
Test regulation : FCC Part 15 Subpart C: 2019
* NFC part
Test Result : Complied (Refer to SECTION 3.2)
Test Item : Spurious Emission
Purpose of test : spot check

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4. The test results in this test report are traceable to the national or international standards.
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It does not cover administrative issues such as Manual or non-Radio test related Requirements. (if applicable)
7. The all test items in this test report are conducted by UL Japan, Inc. Shonan EMC Lab.
8. The opinions and the interpretations to the result of the description in this report are outside scopes where UL Japan has been accredited.
9. The information provided from the customer for this report is identified in SECTION 1.
10. This report is a revised version of 12656071S-V. 12656071S-V is replaced with this report.

Date of test: December 24, 2018

Representative test engineer: 
Makoto Hosaka
Engineer
Consumer Technology Division

Approved by: 
Akio Hayashi
Leader
Consumer Technology Division



- ☐ The testing in which "Non-accreditation" is displayed is outside the accreditation scopes in UL Japan.
☒ There is no testing item of "Non-accreditation".

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REVISION HISTORY

Original Test Report No.: 12656071S-V

Revision	Test report No.	Date	Page revised	Contents
- (Original)	12656071S-V	July 30, 2019	-	-
1	12656071S-V-R1	September 27, 2019	5	Addition of product description as below, The EUT is intended to be used for software development or events.

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SECTION 1: Customer information

Company Name	:	Nintendo Co., Ltd.
Address	:	11-1 Hokotate-cho, Kamitoba, Minami-ku, Kyoto 601-8501, Japan
Telephone Number	:	+81-75-662-9600
Facsimile Number	:	+81-75-662-9624
Contact Person	:	Kazuya Kuramoto

The information provided from the customer is as follows;

- Applicant, Type of Equipment, Model No., FCC ID on the cover and other relevant pages
 - Operating/Test Mode(s) (Mode(s)) on all the relevant pages
 - SECTION 1: Customer information
 - SECTION 2: Equipment under test (E.U.T.)
 - SECTION 4: Operation of E.U.T. during testing
- * The laboratory is exempted from liability of any test results affected from the above information in SECTION 2 and 4.

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment	:	Game Console
Model No.	:	HDH-002
Serial No.	:	Refer to Section 4.2
Rating	:	DC 3.8 V (battery), AC Adapter input: AC 100 V - 240 V, 50 Hz / 60 Hz, 1 A, AC Adapter output: DC 5 V - DC 15 V, 2.6 A
Receipt Date of Sample (Information from test lab.)	:	December 19, 2018
Country of Mass-production	:	China
Condition of EUT	:	Engineering prototype (Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT	:	No Modification by the test lab.

2.2 Product Description

Model: HDH-002 (referred to as the EUT in this report) is a Game Console.

Radio Specification

Wireless LAN, Bluetooth part:

Equipment type	: Transmitter
Frequency of operation	: Wireless LAN part: (2.4 GHz): 2412 MHz - 2472 MHz, (U-NII-1): 5180 MHz - 5240 MHz, (U-NII-2A): 5260 MHz - 5320 MHz, Bluetooth (BDR/EDR/BTLE) part: 2402 MHz - 2480 MHz
Radio part clock frequency	: 37.4 MHz
Channel spacing	: Wireless LAN part: (2.4 GHz): 5 MHz, (5 GHz): 20 MHz, Bluetooth part: (BDR/EDR): 1 MHz, (BT LE): 2 MHz
Type of modulation	: Wireless LAN part: 2.4 GHz bands: DBPSK, DQPSK, CCK, OFDM, 5 GHz bands: OFDM Bluetooth (BT) part: BDR (Basic Data Rate): GFSK, EDR (Enhanced Data Rate): $\pi/4$ -DQPSK, 8DPSK, BT LE (Low Energy mode): GFSK
Antenna type	: Sheet metal antenna
Antenna connector type	: (Ant: 0): MHF2, (Ant: 1): MHF2
Antenna gain	: 2.4 GHz bands: (Ant: 0): -0.904 dBi, (Ant: 1): -0.730 dBi 5 GHz bands: (Ant: 0): 2.949 dBi, (Ant: 1): 1.994 dBi
Power Supply (radio part input)	: DC 1.8 V, DC 3.3 V
Operation temperature range	: +5 deg.C to +35 deg.C

Remarks: This wireless module consists of 1 chip each of 5 GHz bands and 2.4 GHz bands.

(NFC part)

Equipment type	: Transmitter
Frequency of operation	: 13.56 MHz
Radio part clock frequency	: 27.12 MHz
Type of modulation	: ASK
Power Supply (radio part input)	: DC 1.8 V, DC 5.0 V
Antenna type	: Ferrite Chip Antenna
Operation temperature range	: +5 deg.C to +35 deg.C

SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C
 FCC Part 15 final revised on July 19, 2019 and effective August 19, 2019 except 15.258

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
 Section 15.207 Conducted limits
 Section 15.209 Radiated emission limits, general requirements
 Section 15.215 Additional provisions to the general radiated emission limitations.
 Section 15.225 Operation within the bands 13.110 - 14.010 MHz.

* The revisions made after testing date do not affect the test specification applied to the EUT.

* Also the EUT complies with FCC Part 15 Subpart B.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Electric field strength of fundamental emission	ANSI C63.10:2013 6. Standard test methods	FCC 15.225 (a)	56.3 dB (Vertical, QP)	Complied a)	Radiated
	RSS-Gen 6.4, 6.12	RSS-210 B.6			
Electric field strength of outside the allocated bands	ANSI C63.10:2013 6. Standard test methods	FCC 15.225 (b)(c)	37.5 dB (14.195 MHz, Vertical, QP)	Complied a)	Radiated
	RSS-Gen 6.4, RSS-Gen 6.13	RSS-210 B.6			
Electric field strength of spurious emission	ANSI C63.10:2013 6. Standard test methods	FCC 15.209 FCC 15.225 (d)	4.7 dB (40.620 MHz, Vertical, QP)	Complied# a)	Radiated
	RSS-Gen 6.4, 6.13	RSS-210 B.6			
	RSS-Gen 6.11, 8.11	RSS-210 B.6			
Note: UL Japan's EMI Work Procedures No.13-EM-W0420 and 13-EM-W0422.					
a) Refer to APPENDIX 1 (data of Radiated emission)					
Symbols:					
Complied	The data of this test item has enough margin, more than the measurement uncertainty.				
Complied#	The data of this test item meets the limits unless the measurement uncertainty is taken into consideration.				

FCC Part 15.31 (e)

This EUT provides the stable voltage constantly to RF Module regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

There is no applicable rule of uncertainty in this applied standard. Therefore, the results are derived depending on whether or not laboratory uncertainty is applied.

The following uncertainties have been calculated to provide a confidence level of 95 % using a coverage factor $k=2$.

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Item	Frequency range	Uncertainty (+/-)				
		No. 1 SAC / SR	No. 2 SAC / SR	No. 3 SAC / SR	No. 4 SAC / SR	No. 5,6,8 SR
Conducted emission (AC Mains) LISN	150 kHz-30 MHz	2.9 dB	2.8 dB	2.9 dB	2.9 dB	2.9 dB
Radiated emission (Measurement distance: 3 m)	9 kHz-30 MHz	3.0 dB	3.0 dB	3.1 dB	-	-
	30 MHz-200 MHz	4.6 dB	4.6 dB	4.7 dB	-	-
	200 MHz-1 GHz	6.0 dB	6.0 dB	6.1 dB	-	-
	1 GHz-6 GHz	4.8 dB	4.8 dB	4.8 dB	-	-
	6 GHz-18 GHz	5.4 dB	5.4 dB	5.4 dB	-	-
	18 GHz-40 GHz	5.6 dB	5.6 dB	5.6 dB	-	-

SAC=Semi-Anechoic Chamber

SR= Shielded Room is applied besides radiated emission

Antenna terminal test	Uncertainty (+/-)
Bandwidth Measurement	0.61 %
Frequency Measurement	2.9 E-5
Temperature	0.59 deg.C.
Humidity	3.60%
Voltage	0.74%

3.5 Test Location

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JAB Accreditation No. RTL02610 (FCC Test Firm Registration Number: 839876, ISED Lab Company Number: 2973D)

Test site	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Maximum measurement distance
No.1 Semi-anechoic chamber	20.6 x 11.3 x 7.65	20.6 x 11.3	10 m
No.2 Semi-anechoic chamber	20.6 x 11.3 x 7.65	20.6 x 11.3	10 m
No.3 Semi-anechoic chamber	12.7 x 7.7 x 5.35	12.7 x 7.7	5 m
No.4 Semi-anechoic chamber	8.1 x 5.1 x 3.55	8.1 x 5.1	-
No.1 Shielded room	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.2 Shielded room	6.8 x 4.1 x 2.7	6.8 x 4.1	-
No.3 Shielded room	6.3 x 4.7 x 2.7	6.3 x 4.7	-
No.4 Shielded room	4.4 x 4.7 x 2.7	4.4 x 4.7	-
No.5 Shielded room	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.6 Shielded room	7.8 x 6.4 x 2.7	7.8 x 6.4	-
No.8 shielded room	3.45 x 5.5 x 2.4	3.45 x 5.5	-
No.1 Measurement room	2.55 x 4.1 x 2.5	-	-

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Test item	Operating mode	Tested frequency
All items except for Frequency Tolerance	Transmitting 13.56 MHz	13.56 MHz
Frequency Tolerance	Transmitting 13.56 MHz (Non-modulated)	13.56 MHz

Software for testing: Controller NFC Checker Ver.B.01

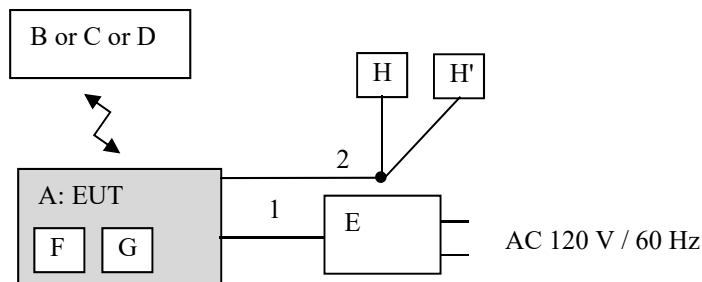
Power setting: Fixed

The carrier level and noise levels were confirmed with and without Tag, and the test was made with the condition that has the maximum noise.

Combinations of the worst case:

Radiated emission (Carrier)	Radiated emission (Below 30 MHz)	Radiated emission (Above 30 MHz)
With Tag (Type F)	With Tag (Type F)	With Tag (Type F)

4.2 Configuration and peripherals



* Test data was taken under worse case conditions.

Description of EUT and support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Game Console	HDH-002	XJW01000021132	Nintendo Co., Ltd.	EUT
B	Tag (type A)	NVL-001	-	Nintendo Co., Ltd.	Type A
C	Tag (type B)	-	-	-	Type B
D	Tag (type F)	-	-	-	Type F
E	AC Adapter	HAC-002	-	Nintendo Co., Ltd.	-
F	Game Card	HAC-008	DFCAA22L000	Nintendo Co., Ltd.	-
G	Micro SD Card	-	-	Transcend	-
H, H'	Headphone	-	-	Nintendo Co., Ltd.	-

List of cables used

No.	Cable Name	Length (m)	Shield		Remark
			Cable	Connector	
1	USB	1.8	Shielded	Shielded	-
2	Headphone	0.5 + 0.3	Unshielded	Unshielded	-

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SECTION 5: Radiated Emission (Electric field strength of Fundamental emission and Spurious emission within the band)

Test Procedure

EUT was placed on a platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane. The table is made of expanded polystyrol and expanded polypropylene and the table top is covered with polycarbonate. That has very low permittivity.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

Although these tests were performed other than open area test site, adequate comparison measurements were confirmed against 30 m open area test site. Therefore sufficient tests were made to demonstrate that the alternative site produces results that correlate with the ones of tests made in an open field based on KDB 414788.

These tests were performed in semi anechoic chamber. Therefore the measured level of emissions may be higher than if measurements were made without a ground plane.

However test results were confirmed to pass against standard limit.

The Radiated Electric Field Strength intensity has been measured with a ground plane and at a distance of 3 m.

Frequency: From 9 kHz to 30 MHz at distance 3 m (Refer to Figure 2)

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for vertical polarization (antenna angle: 0 deg., 45 deg., 90 deg. and 135 deg.) and horizontal polarization. Drawing of the antenna direction is shown in Figure 1.

Frequency: From 30 MHz to 1 GHz at distance 3 m (Refer to Figure 2).

The measuring antenna height was varied between 1 m and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver.

	9 kHz to 90 kHz & 110 kHz to 150 kHz	90 kHz to 110 kHz	150 kHz to 490 kHz	490 kHz to 30 MHz	30 MHz to 1 GHz
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200 Hz	200 Hz	10 kHz	9 kHz	120 kHz
Distance factor *1)	-80 dB	-80 dB	-80 dB	-40 dB	-
Measuring antenna	Loop antenna				Biconical (30 MHz - 199.99 MHz) Logperiodic (200 MHz - 1 GHz)

*1) FCC 15.31 (f)(2) (9 kHz-30 MHz)

Distance Factor: $40 \times \log(3 \text{ m} / 300 \text{ m}) = -80 \text{ dB}$

Distance Factor: $40 \times \log(3 \text{ m} / 30 \text{ m}) = -40 \text{ dB}$

Figure 1: Direction of the Loop Antenna

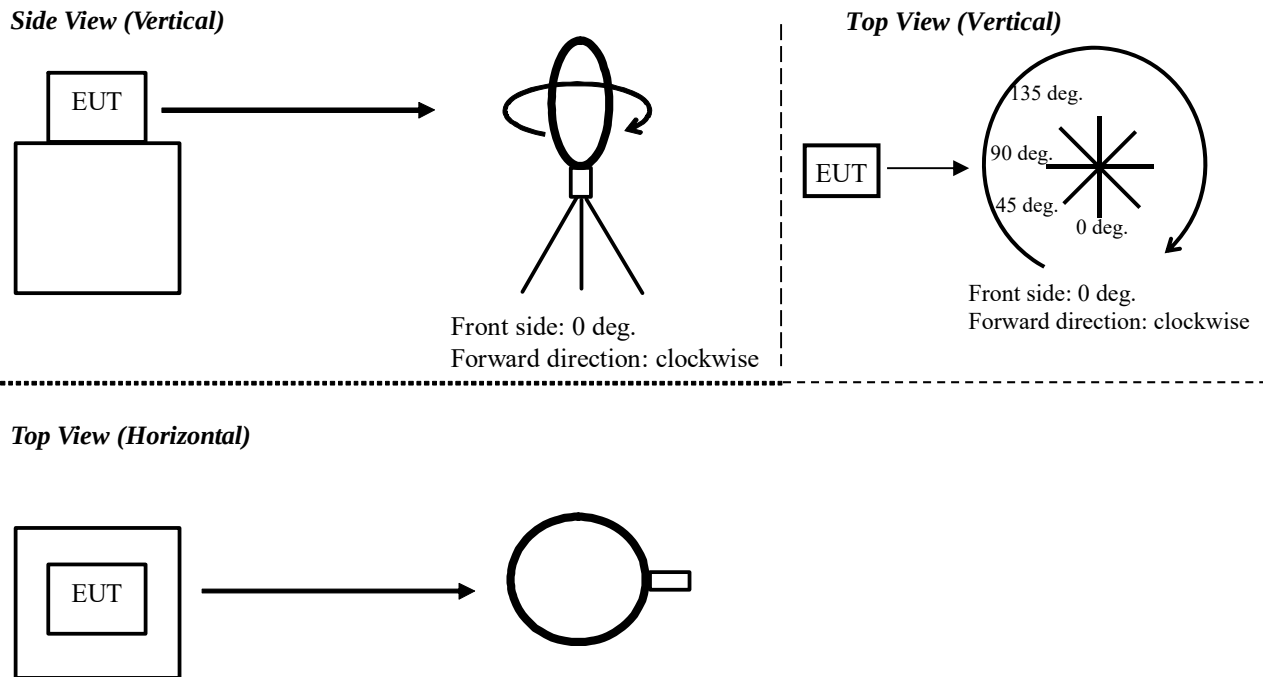
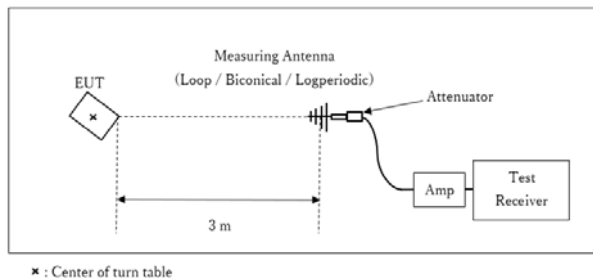


Figure 2: Test Setup
Below 1 GHz



Test Distance: 3 m

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Antenna polarization	Below 30 MHz	Above 30 MHz
Horizontal	Y	X
Vertical	Z	X

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 9 kHz - 1 GHz
Test data : APPENDIX
Test result : Pass

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Radiated Emission

Electric field strength of Fundamental emission and Spurious emission within the band: FCC15.225(a)(b)(c)

UL Japan, Inc.
Shonan EMC Lab., No.2 Semi Anechoic Chamber

Company: Nintendo Co., Ltd. Equipment: Game Console Model: HDH-002 Sample No.: XJW01000021132 Power: AC 120 V/ 60 Hz (AC adaptor input) Mode: Transmitting 13.56 MHz	Regulation: FCC Part15 Subpart C 15.225 Test Distance: 3 m Date: December 24, 2018 Temperature: 18 deg.C Humidity: 42 %RH ENGINEER: Makoto Hosaka
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Remarks: : NFC type F (Axis: Ver_Z) , Vertical polarization (antenna angle) of the worst case: 0deg

Fundamental emission

No.	FREQ [MHz]	Test Receiver Reading		Antenna Factor [dB/m]	Loss [dB]	AMP GAIN [dB]	Distance factor [dB]	RESULT		LIMIT (30 m) [dBuV/m]	MARGIN	
			Ver [dBuV]						Ver [dBuV/m]			Ver [dB]
1	13.560		73.8	19.1	6.6	31.9	-40.0		27.6	83.9		56.3

Calculation: Result[dBuV/m] = Reading[dBuV] + Ant.Fac[dB/m] + Loss(Cable+ATT)[dB] - Gain(AMP)[dB] + Distance factor[dB]

Distance factor: $40 \times \log(3 \text{ m}/30 \text{ m}) = -40 \text{ dB}$

Limits (30 m)

• 13.553 MHz to 13.567 MHz : 83.9 dBuV/m (FCC 15.225(a))

Spurious emission within the band

No.	FREQ [MHz]	Test Receiver Reading		Antenna Factor [dB/m]	Loss [dB]	AMP GAIN [dB]	Distance factor [dB]	RESULT		LIMIT (30 m) [dBuV/m]	MARGIN	
			Ver [dBuV]						Ver [dBuV/m]			Ver [dB]
1	12.925		35.9	19.2	6.6	31.9	-40.0		-10.2	29.5		39.7
2	13.110		30.2	19.2	6.6	31.9	-40.0		-16.0	29.5		45.5
3	13.348		45.7	19.2	6.6	31.9	-40.0		-0.5	40.5		41.0
4	13.410		33.9	19.2	6.6	31.9	-40.0		-12.3	40.5		52.8
5	13.553		58.6	19.1	6.6	31.9	-40.0		12.4	50.4		38.0
6	13.567		59.1	19.1	6.6	31.9	-40.0		12.9	50.4		37.5
7	13.710		34.5	19.1	6.6	31.9	-40.0		-11.8	40.5		52.3
8	13.772		46.8	19.1	6.6	31.9	-40.0		0.5	40.5		40.0
9	14.010		30.2	19.1	6.6	31.9	-40.0		-16.1	29.5		45.6
10	14.195		38.3	19.0	6.6	31.9	-40.0		-8.0	29.5		37.5

Calculation: Result[dBuV/m] = Reading[dBuV] + Ant.Fac[dB/m] + Loss(Cable+ATT)[dB] - Gain(AMP)[dB] + Distance factor[dB]

Outside filed strength frequencies

- $F_c \pm 7 \text{ kHz}$: 13.553 MHz to 13.567 MHz
- $F_c \pm 150 \text{ kHz}$: 13.410 MHz to 13.710 MHz
- $F_c \pm 450 \text{ kHz}$: 13.110 MHz to 14.010 MHz

$F_c = 13.56 \text{ MHz}$

Limits (30 m)

- 13.410 MHz to 13.553 MHz and 13.567 MHz to 13.710 MHz : 50.4 dBuV/m (FCC 15.225(b))
- 13.110 MHz to 13.410 MHz and 13.710 MHz to 14.010 MHz : 40.5 dBuV/m (FCC 15.225(c))
- Below 13.110 MHz and Above 14.010 MHz : 29.5 dBuV/m (FCC 15.225(d) and FCC 15.209)

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Shonan EMC Lab. No.2 Semi Anechoic Chamber

Regulation: FCC Part15 Subpart C 15.225
Test Distance: 3 m
Date: December 24, 2018
Temperature: 18 deg.C
Humidity: 42 %RH
ENGINEER: Makoto Hosaka

$$\text{Result} = \text{Reading} + \text{Ant Factor} + \text{Loss (Cable+ATT+\Delta AF(above 30 MHz))} - \text{Gain(Amprifier)} + \text{Distance factor(below 30 MHz)}$$

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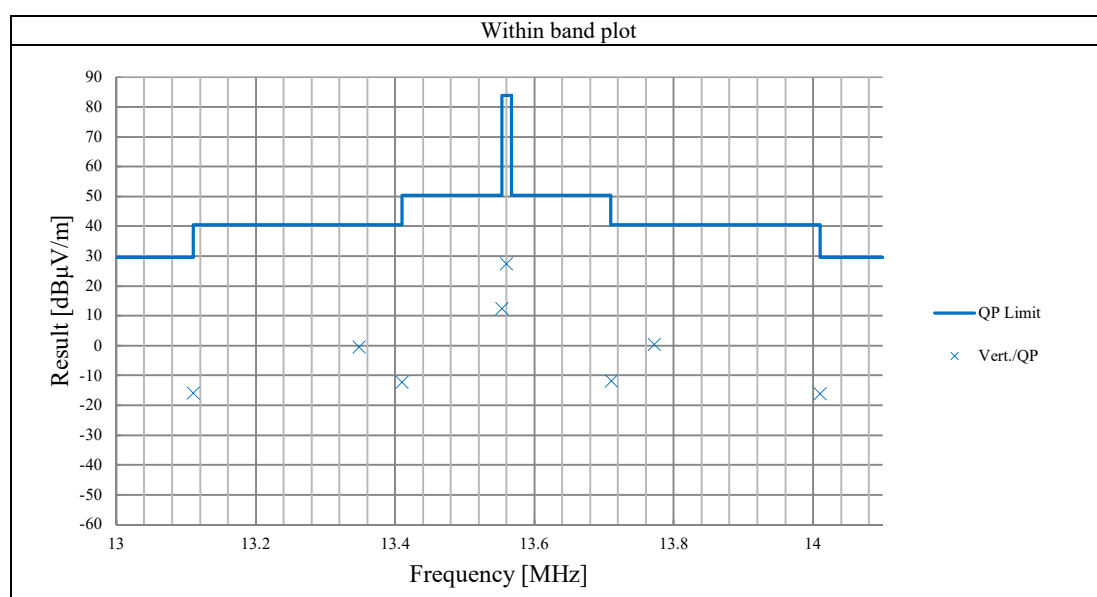
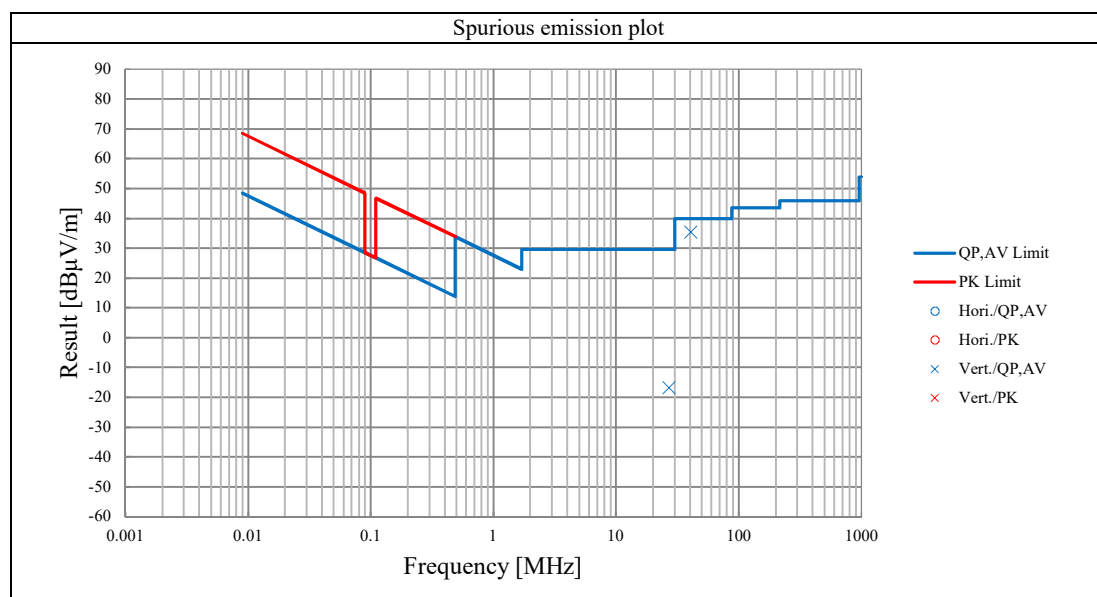
Radiated Emission (Worst mode plot)

UL Japan, Inc.
Shonan EMC Lab. No.2 Semi Anechoic Chamber

Company: Nintendo Co., Ltd.
Equipment: Game Console
Model: HDH-002
Sample No.: XJW01000021132
Power: AC 120 V/ 60 Hz (AC adaptor input)
Mode: Transmitting 13.56 MHz
EUT axis: Below 30 MHz(Vertical: Z-axis), NFC type F, with Tag
Above 30 MHz(Vertical: X-axis), NFC type F, with Tag

Regulation: FCC Part15 Subpart C 15.225
Test Distance: 3 m
Date: December 24, 2018
Temperature: 18 deg.C
Humidity: 42 %RH
ENGINEER: Makoto Hosaka

Remarks: These plots data contains sufficient number to show the trend of characteristic features for EUT.



APPENDIX 2**Test Instruments****EMI test equipment**

Local ID	Test Name	LIMS ID	Description	Manufacturer	Model	Serial	Last Calibration Date	Calibration Due Date	Calibration Interval (Month)
COTS-SEMI-5	RE	170932	EMI Software	TSJ	TEPTO-DV3(RE,CE,ME,PE)	-	-	-	-
SAEC-02(NSA)	RE	145563	Semi-Anechoic Chamber	TDK	SAEC-02(NSA)	2	2018/5/31	2019/5/31	12
SAF-02	RE	145004	Pre Amplifier	SONOMA	310N	290212	2019/2/5	2020/2/29	12
SAT3-11	RE	150921	Attenuator	JFW	50HF-003N	-	2019/1/25	2020/1/31	12
SAT6-02	RE	145045	Attenuator	JFW	50HF-006N	-	2019/2/5	2020/2/29	12
SAT6-12	RE	145158	Attenuator	HIROSE ELECTRIC	AT-406(40)	-	2018/8/23	2019/8/31	12
SBA-02	RE	145022	Biconical Antenna	Schwarzbeck	BBA9106	91032665	2018/6/5	2019/6/30	12
SCC-B1/B3/B5/B7/B8/B13/SRSE-02	RE	144975	Coaxial Cable&RF Selector	Fujikura/Fujikura/Suhner/Suhner/Suhner/TOYO	8D2W/12DSFA/141PE/141PE/141PE/141PE/141PE/141P	-/0901-270(RF Selector)	2018/4/9	2019/4/30	12
SCC-B2/B4/B6/B7/B8/B13/SRSE-02	RE	144976	Coaxial Cable&RF Selector	Fujikura/Fujikura/Suhner/Suhner/Suhner/TOYO	8D2W/12DSFA/141PE/141PE/141PE/141PE/141PE/141P	-/0901-270(RF Selector)	2018/4/7	2019/4/30	12
SJM-09	RE	145336	Measure	PROMART	SEN1935	-	-	-	-
SLA-06	RE	145528	Logperiodic Antenna	Schwarzbeck	VUSLP9111B	195	2018/6/5	2019/6/30	12
SLP-02	RE	145536	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100218	2018/10/10	2019/10/31	12
SOS-03	RE	146317	Humidity Indicator	A&D	AD-5681	4063325	2018/10/25	2019/10/31	12
STR-07	RE	146209	Test Receiver	Rohde & Schwarz	ESU26	100484	2018/9/26	2019/9/30	12
STS-02	RE	145793	Digital Hitester	HIOKI	3805-50	80997819	2018/3/8	2019/3/31	12

*Hyphens for Last Calibration Date, Calibration Due Date and Cal Int (month) are instruments that Calibration is not required (e.g. software), or instruments checked in advance before use.

The expiration date of the calibration is the end of the expired month.

As for some calibrations performed after the tested dates , those test equipment have been controlled by means of an unbroken chains of calibrations .

All equipment is calibrated with valid calibrations . Each measurement data is traceable to the national or international standards

Test Item:

RE: Radiated emission